



<b>Interference Searched</b>  	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10635314	ONITSUKA ET AL.
	Examiner Chang, Rick K	Art Unit 3729

Class	SubClass	Date	Examiner
29,248,269	subs. under searched	6/5/06	RC

U.S. Patent and Trademark Office	Part of Paper No.: 20060605
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search updated

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<b>Search Notes</b>  	Application/Control No.  10635314	Applicant(s)/Patent Under Reexamination  ONITSUKA ET AL.
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east search

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